## Notice of References Cited Application/Control No. 10/561,908 Applicant(s)/Patent Under Reexamination SUENAGA ET AL. Examiner DAVID T. WELCH Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0001410 A1	01-2002	Hagiwara, Shinichi	382/232
*	В	US-2003/0147563 A1	08-2003	Liu et al.	382/276
*	С	US-2004/0263533 A1	12-2004	Yamamoto et al.	345/619
*	D	US-6,967,675 B1	11-2005	Ito et al.	348/207.1
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	I	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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